

ICEM Scan

Measurement Service for IC Emission with Stripline acc. to IEC/TS 61967-3

LANGER
EMV-Technik

Short description

The ICEM Scan measurement service determines the near-field electrical or magnetical components on or near the surface of an IC in accordance with the IEC/TS 61967-3 standard. This diagnostic procedure is used for architectural analysis of an IC such as manufacturing planning and optimization of power distribution. This test method is applicable to measurements of an IC mounted on an in-function printed circuit board that is accessible to the scanning probe.